

Notice of References Cited		Application/Control No.	Applicant(s)/Patent Under Reexamination SHIONO ET AL.	
		Examiner Henok G. Heyi	Art Unit 2627	Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-5,080,947 A	01-1992	Yamada et al.	428/64.4
*	B	US-5,614,938 A	03-1997	Sugiyama et al.	347/247
*	C	US-5,698,344 A	12-1997	Bai et al.	430/1
	D	US-			
	E	US-			
	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

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	N					
	O					
	P					
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	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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	V	
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	X	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
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